

RENESAS TECHNICAL UPDATE

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Product Category	MPU/MCU		Document No.	TN-RX*-A0274A/E	Rev.	1.00
Title	Errata to the RX26T Group User's Manual: Hardware regarding the Electrical Characteristics of the Code Flash Memory		Information Category	Technical Notification		
Applicable Product	RX26T Group	Lot No.	Reference Document	RX26T Group User's Manual: Hardware Rev.1.10 (R01UH0979EJ0110)		
		All				

This document describes corrections regarding the program time and erase time of code flash memory described in the section on the electrical characteristics of the RX26T Group User's Manuals: Hardware Rev.1.10.

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The characteristics of program time and erase time in Table 49.53, Code Flash Memory Characteristics in section 49.12, Flash Memory Characteristics are corrected as follows.

Before correction

Table 49.53 Code Flash Memory Characteristics

Conditions: VCC = 2.7 to 5.5 V, AVCC0 = AVCC1 = AVCC2 = 3.0 to 5.5 V,
VSS = AVSS0 = AVSS1 = AVSS2 = 0 V,
Temperature range for program/erase: T_a = T_{opr}

Item		Symbol	FCLK = 4 MHz			20 MHz ≤ FCLK ≤ 60 MHz			Unit	Test Conditions
			Min.	Typ.	Max.	Min.	Typ.	Max.		
Program time (NPEC ≤ 100 cycles)	128 bytes	t _{P128}	—	0.66	11	—	0.3	5	ms	
	8 Kbytes	t _{P8K}	—	37	176	—	17	80		
	32 Kbytes	t _{P32K}	—	150	704	—	68	320		
Program time (NPEC > 100 cycles)	128 bytes	t _{P128}	—	0.71	13	—	0.32	6	ms	
	8 Kbytes	t _{P8K}	—	46	212	—	21	96		
	32 Kbytes	t _{P32K}	—	185	848	—	84	384		
Erase time (NPEC ≤ 100 cycles)	4 Kbytes	t _{E4K}	—	43	108	—	24	60	ms	
	32 Kbytes	t _{E32K}	—	284	864	—	158	480		
Erase time (NPEC > 100 cycles)	4 Kbytes	t _{E4K}	—	50	130	—	28	72	ms	
	32 Kbytes	t _{E32K}	—	338	864	—	188	480		
(Omitted)										

After correction

Table 49.53 Code Flash Memory Characteristics

Conditions: VCC = 2.7 to 5.5 V, AVCC0 = AVCC1 = AVCC2 = 3.0 to 5.5 V,

VSS = AVSS0 = AVSS1 = AVSS2 = 0 V,

Temperature range for program/erase: T_a = T_{opr}

Item		Symbol	FCLK = 4 MHz			20 MHz ≤ FCLK ≤ 60 MHz			Unit	Test Conditions
			Min.	Typ.	Max.	Min.	Typ.	Max.		
Program time (NPEC ≤ 100 cycles)	128 bytes	t _{P128}	—	0.66	11	—	0.3	5	ms	
	8 Kbytes	t _{P8K}	—	37	176	—	17	80		
	16 Kbytes	t _{P16K}	—	75	352	—	34	160		
Program time (NPEC > 100 cycles)	128 bytes	t _{P128}	—	0.71	13	—	0.32	6	ms	
	8 Kbytes	t _{P8K}	—	46	212	—	21	96		
	16 Kbytes	t _{P16K}	—	92	425	—	42	193		
Erase time (NPEC ≤ 100 cycles)	4 Kbytes	t _{E4K}	—	43	108	—	24	60	ms	
	16 Kbytes	t _{E16K}	—	142	432	—	79	240		
Erase time (NPEC > 100 cycles)	4 Kbytes	t _{E4K}	—	50	130	—	28	72	ms	
	16 Kbytes	t _{E16K}	—	169	520	—	94	288		

(Omitted)